

Lensless Imaging of 3D Nanostructures using Soft X-Rays

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100 W // 68 W
30 fs, 500 kHz

Narrow spectral peaks 0.2 nm at 30 nm up to 8 nm

High Harmonic Generation

Extreme UV and Soft X-Rays

Material inspection with EUV/SXR light

Coherent Diffractive Imaging - Ptychography

Phase Retrieval of Far Field Diffraction Patterns

EUV Multilayer Focusing Optics

Nanostructure Inspection

Active Lithographic Mask

Interested in reflective optical design courses?
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